

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/767,628	BENNARD, MIKE	
Examiner Kevin Gutierrez		Art Unit 2851	Page 1 of 1	

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-2002/0075469 A1	06-2002	Tanaka, Keiichi	355/72
B	US-2003/0184724 A1	10-2003	Ono et al.	355/72
C	US-5,040,431	08-1991	Sakino et al.	74/490.09
D	US-2004/0145715 A1	07-2004	Takashima, Tsuneo	355/072
E	US-2003/0067592 A1	04-2003	Tim Poon et al.	355/75
F	US-6,597,435 B2	07-2003	Poon et al.	355/75
G	US-5,504,407 A	04-1996	Wakui et al.	318/568.17
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
U			
V			
W			
X			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.